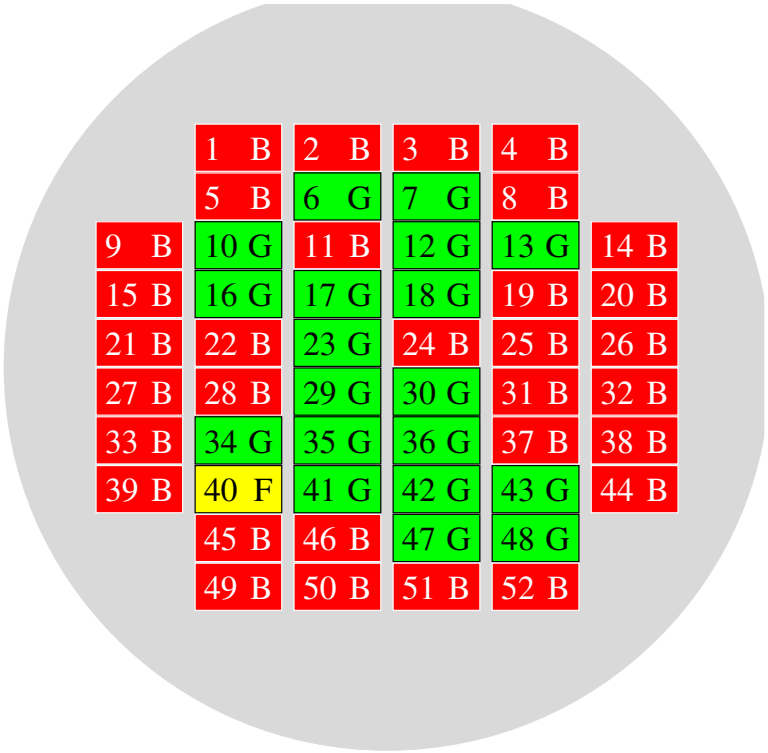
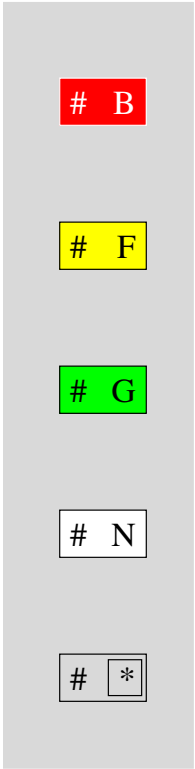
Die quality map for wafer 32 s/n: 21316-06-15

Date: 11/01/98





Bad die

Fair die

Good die

No info

Manually tagged